Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination SHANNON, KAREN W.	
10/686,092		
Examiner	Art Unit	

1631

Pablo Whaley

SEARCHED				
Class	Subclass	Date	Examiner	
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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(INCLUDING SEARCH	DATE	EXMR
	DATE	LAIVIN
Google Scholar: candidate probe sequence, selection, distance from 3' end, array, clustering	7/24/2007	PW
EAST: see attached	7/25/2007	PW
Inventor search: palm	7/25/2007	pw
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